# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

**PLED** 

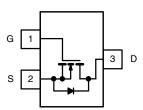
# Brodnet data speet

www.msksemi.com





SOT-23



#### **Features**

- 20V, 3A, RDS(ON) = $40m\Omega@VGS = 4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

#### **Applications**

- Notebook
- Load Switch
- Hend-Held Instruments

BVDSS	RDSON	ID
20V	40m $Ω$	3A

#### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	20	V
V <sub>GS</sub>	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T <sub>C</sub> =25°C)	3	Α
ID	Drain Current – Continuous (T <sub>C</sub> =100°C)	2	А
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	16	А
D	Power Dissipation (T <sub>C</sub> =25°C)	1.56	W
P <sub>D</sub>	Power Dissipation – Derate above 25°C	0.012	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		80	°C/W



#### **Electrical Characteristics** (T<sub>J</sub>=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions		Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	20			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.02		V/°C
	Prain Source Leekage Current	V <sub>DS</sub> =20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±12V , V <sub>DS</sub> =0V			±100	nA

#### **On Characteristics**

Б		V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A		40	55	mΩ	
R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =2.5V , I <sub>D</sub> =1A		55	75	11152	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA		0.5	1	V	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			2		mV/°C	
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>S</sub> =2A		4.4		S	

#### **Dynamic and switching Characteristics**

•	• • • • • • • • • • • • • • • • • • • •			
Qg	Total Gate Charge <sup>2, 3</sup>		 3.6	
$Q_gs$	Gate-Source Charge <sup>2, 3</sup>	V <sub>DS</sub> =10V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =1A	 0.38	 nC
$Q_gd$	Gate-Drain Charge <sup>2, 3</sup>		 0.6	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 1.8	
Tr	Rise Time <sup>2 , 3</sup>	$V_{DD}$ =10V , $V_{GS}$ =4.5V , $R_{G}$ =25 $\Omega$	 5.6	 nS
$T_{d(off)}$	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =1A	 11.3	 113
T <sub>f</sub>	Fall Time <sup>2 , 3</sup>		 3.2	
C <sub>iss</sub>	Input Capacitance		 180	
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , F=1MHz	 32	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 26	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V =V =0V Force Current			3	Α
I <sub>SM</sub>	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			6	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 3. Essentially independent of operating temperature.



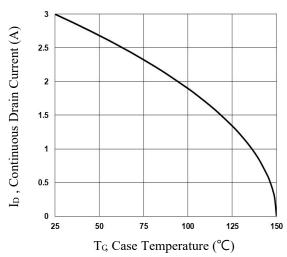


Fig.1 Continuous Drain Current vs. Tc

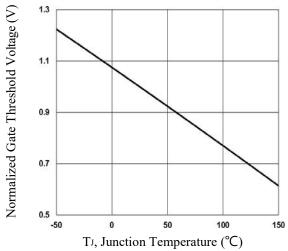


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

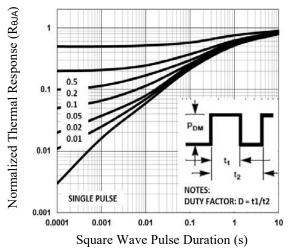


Fig.5 Normalized Transient Impedance

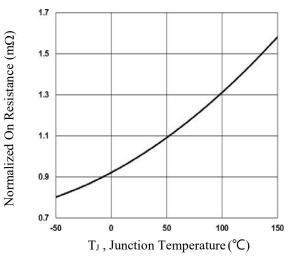


Fig.2 Normalized RDSON vs. TJ

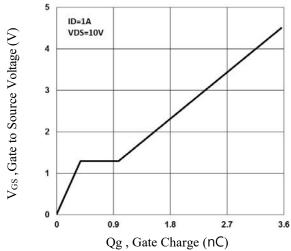


Fig.4 Gate Charge Waveform

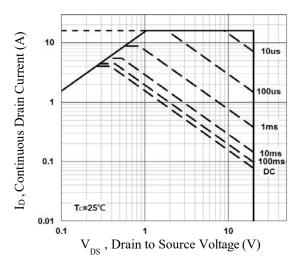
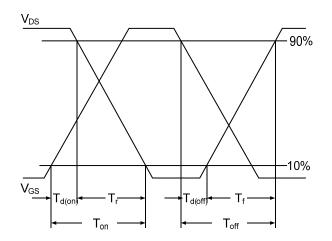


Fig.6 Maximum Safe Operation Area



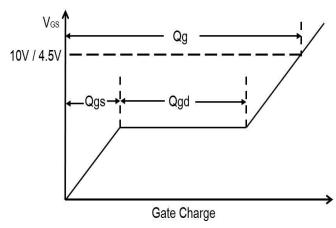


Fig.7 Switching Time Waveform

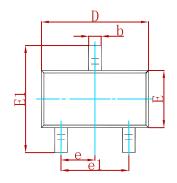
Fig.8 Gate Charge Waveform

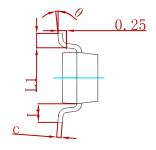


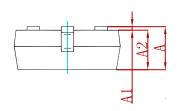




#### **PACKAGE MECHANICAL DATA**

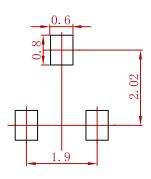






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950	) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550	0.550 REF		REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
SI2302CDS-T1-GE3-MS	SOT-23	3000

Semiconductor Compiance

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